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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/711,748	10/01/2004	Kiran V. Chatty	BUR920040050US1	5747
44152	7590	04/05/2005	EXAMINER	
GREENBLUM & BERNSTEIN, P.L.C. 1950 ROLAND CLARK DRIVE RESTON, VA 20191			KITOV, ZEEV	
			ART UNIT	PAPER NUMBER
			2836	

DATE MAILED: 04/05/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

## Office Action Summary

Application No.

10/711,748

Applicant(s)

CHATTY ET AL.

Examiner

Zeev Kitov

Art Unit

2836

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --  
**Period for Reply**

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

### Status

- 1) ☒ Responsive to communication(s) filed on 01 October 2004.  
2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.  
3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

### Disposition of Claims

- 4) ☒ Claim(s) 1 - 20 is/are pending in the application.  
4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.  
5) ☐ Claim(s) \_\_\_\_\_ is/are allowed.  
6) ☒ Claim(s) 1 - 20 is/are rejected.  
7) ☐ Claim(s) \_\_\_\_\_ is/are objected to.  
8) ☐ Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

### Application Papers

- 9) ☐ The specification is objected to by the Examiner.  
10) ☒ The drawing(s) filed on 01 October 2004 is/are: a) ☐ accepted or b) ☒ objected to by the Examiner.  
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).  
11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

### Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).  
a) ☐ All b) ☐ Some \* c) ☐ None of:  
1. ☐ Certified copies of the priority documents have been received.  
2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.  
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).  
\* See the attached detailed Office action for a list of the certified copies not received.

### Attachment(s)

- 1) ☒ Notice of References Cited (PTO-892)  
2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)  
3) ☒ Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  
Paper No(s)/Mail Date 03/01/05.  
4) ☐ Interview Summary (PTO-413)  
Paper No(s)/Mail Date. \_\_\_\_\_.  
5) ☐ Notice of Informal Patent Application (PTO-152)  
6) ☐ Other: \_\_\_\_\_.

## DETAILED ACTION

### *Drawings*

The drawings are objected to under 37 CFR 1.83(a). The drawings must show every feature of the invention specified in the claims. Therefore, the “third nFET connected in series with the first nFET and the second nFET” recited in Claims 3 and 4 must be shown or the feature(s) canceled from the claim(s). No new matter should be entered.

Corrected drawing sheets in compliance with 37 CFR 1.121(d) are required in reply to the Office action to avoid abandonment of the application. Any amended replacement drawing sheet should include all of the figures appearing on the immediate prior version of the sheet, even if only one figure is being amended. The figure or figure number of an amended drawing should not be labeled as “amended.” If a drawing figure is to be canceled, the appropriate figure must be removed from the replacement sheet, and where necessary, the remaining figures must be renumbered and appropriate changes made to the brief description of the several views of the drawings for consistency. Additional replacement sheets may be necessary to show the renumbering of the remaining figures. Each drawing sheet submitted after the filing date of an application must be labeled in the top margin as either “Replacement Sheet” or “New Sheet” pursuant to 37 CFR 1.121(d). If the changes are not accepted by the examiner, the applicant will be notified and informed of any required corrective action in the next Office action. The objection to the drawings will not be held in abeyance.

***Claim Rejections - 35 USC § 112***

The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter, which the applicant regards as his invention.

Claims 9 and 14 are rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention. A reason for that is that the claims include a following limitation: "wherein the voltage divider is connected between the pair of power supply rails and comprises a high impedance therebetween". It is not clear, what values or range of values could be considered as "high impedance". Specification is silent on the matter. For purpose of examination it was assumed that any resistance value higher than the internal resistance of the voltage source providing power supply to the circuit would be "a high impedance".

***Claim Rejections - 35 USC § 103***

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

Claims 1, 2, 5 - 8, 10 - 13, 15 - 18, 20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Chen (US 6,556,398) in view of Metz et al. (US 5,400,202).

Chen discloses following elements of Claims 7 and 1: an upper and a lower nFET (elements 13 and 15 in Fig.2) connected in series with one another between a pair of power supply rails, a voltage divider (elements C and 20 in Fig.3) configured to bias a gate of the upper nFET to a prescribed value. However, it does not disclose an low frequency filter. Metz et al. disclose the low frequency filter (elements C and R in Fig. 4a) connected to a gate of the lower nFET (element 18 in Fig. 4a) and configured to filter out low frequency signals between at least one power supply rail and the gate of the lower nFET. Both references have the same problem solving area, namely providing ESD protection for the semiconductor IC's. . Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to have modified the Chen solution by adding the low frequency filter according to Metz et al., because the RC trigger circuit reacts and activates the clamp only for the transients rising faster than the RC element time constant, while the resistive voltage divider of Chen can be triggered by slow rising and even steady voltage; therefore presence of the RC trigger circuit makes the clamp reacting only to the transients.

Regarding Claim 2, Chen discloses the transistor network including a first nFET and a second nFET (elements 13 and 15 in Fig. 2) connected in series with one another between the voltage source and a ground.

Regarding Claims 5 and 15, Chen discloses the bias network (elements 23 and 26 in Fig. 2), a voltage divider communicating a portion of the voltage from the voltage source to the gate of the first transistor (element 13 in Fig. 2). The voltage performs biasing of the transistor gate.

Regarding Claim 6, Metz et al. disclose the trigger network (elements R and C in Fig. 4a) including the resistor and capacitor configured to filter out non-electrostatic discharge events. The RC trigger circuit reacts and activates the clamp only for the transients rising faster than the RC element time constant, while the resistive voltage divider of Chen can be triggered by slow rising and even steady voltage; therefore presence of the RC trigger circuit makes the clamp reacting only to the transients. A motivation for modification of the primary reference is the same as above.

Regarding Claim 8, Chen discloses the gate of the upper nFET being biased to a prescribed fraction of a voltage between the pair of power supply rails (depending on ratio of the elements 23 and 25 in Fig. 2 resistances).

Regarding Claim 10, Chen discloses the voltage divider having at least one resistor (col. 3, lines 42 - 50).

Regarding Claim 11, Metz et al. disclose the low frequency filter (elements C and R in Fig. 4a) communicating with the source and drain of the lower nFET. The RC element is directly connected to the drain of the nFET and when it turns on the nFET through its gate, the drain of the nFET is affected as well. This way the RC filter communicates with the drain of the nFET. A motivation for modification of the primary reference is the same as above.

Regarding Claim 12, Chen discloses configuring a gate of the upper transistor (element 13 in Fig. 2) of a transistor network to be biased to a prescribed value (by a voltage divider, elements 23, 25 in Fig. 2). Metz et al. disclose coupling an electrostatic discharge event from the trigger circuit (elements C and 20 in Fig. 3) to a gate of a

transistor (element MN in Fig. 3) of the transistor network. In the Chen circuit modified according to Metz et al. the electrostatic discharge event is eventually brought to a gate of the lower transistor, since it is the only uncommitted transistor. A motivation for modification of the primary reference is the same as above.

Regarding Claim 13, Chen discloses biasing the gate of the upper transistor (element 13 in Fig. 2) with a voltage divider (elements 23, 25 in Fig.2) connected between the power rails.

Regarding Claim 16, Chen discloses configuring a gate of the upper transistor of a transistor network connected between power rails to be biased to a prescribed value includes applying a voltage obtained by the voltage divider to the gate of the transistor through one power rail (the Vss rail) of the power rails.

Regarding Claim 17, Chen discloses attaching a bias network between one power rail of the power rails (Vss rail in Fig. 2) and the transistor network (the gate of transistor).

Regarding Claim 18, Metz et al. disclose coupling an electrostatic discharge event to a gate of an lower transistor with a high pass filter (elements C and R in Fig. 4a). A motivation for modification of the primary reference is the same as above.

Regarding Claim 20, Chen discloses configuring at least one power rail of the power rails to be in electrical communication with a voltage source (Vss terminal in Fig. 2), and configuring at least one power rail of the power rails to be in electrical communication with ground (the same terminal Vss in Fig. 2).

Claim 19 is rejected under 35 U.S.C. 103(a) as being unpatentable over Chen in view of Metz et al. and Court Decision *In re Boesch*, 617 F.2d 272, 205 USPQ 215 (CCPA 1980). As was stated above, Chen and Metz et al. disclose all the elements of Claims 12 and 18. However, regarding Claim 19, they do not disclose the high pass filter having a time constant of one microsecond. As well known in the art, the condition of passage of the ESD event through the filter requires the front of the ESD event being shorter than the time constant of the filter. On other side, the time constant cannot be too large due to structural and cost limitations. Therefore, the time constant is nothing but the result effective variable. The Court Decision address the issue of selecting a value of the result effective variable stating that discovering an optimum value of the result effective variable involves only routine skill in the art. Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to have further modified the Chen solution by setting the time constant of the high pass filter to a value of one microsecond, since it has been held that discovering an optimum value of a result effective variable involves only routine skill in the art.

Claims 3 and 4 are rejected under 35 U.S.C. 103(a) as being unpatentable over Chen in view of Metz et al. and Court Decision *St. Regis Paper Co. v. Bemis Co.*, 193 USPQ 8. As was stated above, Chen and Metz et al. disclose all the elements of Claims 1 and 2. However, regarding Claims 3 and 4, they do not disclose the third transistor. According to Claims 3 and 4, the third transistor is connected in exactly the same way as the first transistor, i.e. just repeating schematically and functionally the




first transistor. As to possible effect of increasing the breakdown voltage due to such inclusion, this feature was already achieved in Chen's circuit by connecting two transistors in series. Therefore, inclusion of the third transistor is nothing but duplication of essential working parts, which according to the Court Decision, involves only routine skill in the art. Therefore, it would be obvious to one of ordinary skill in the art at the time the invention was made to add the third transistor connected in the same way as the first transistor, since it has been held that mere duplication of the essential working parts involves only routine skill in the art.

Claims 9 and 14 are rejected under 35 U.S.C. 103(a) as being unpatentable over Chen in view of Metz et al. and Gelecinskyi et al. (US 4,916,381). As was stated above, Chen and Metz et al. disclose all the elements of Claims 7 and 12. However, regarding Claims 9 and 14, they do not disclose the voltage divider having high impedance. Gelecinskyi et al. disclose the MOSFET (element 62 in Fig. 1B) being biased by a voltage obtained from the voltage divider (elements 71 and 72 in Fig. 1B). The values of the resistors are 15 Kohm and 30 Kohm respectively, which represent the high impedance. Both references have the same problem solving area, namely providing a bias for the gate of the MOSFET. Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to have further modified the Chen solution by setting the resistors of the voltage divider at high impedance value, because increase of impedance results in reduction of current consumption and heat dissipation.

***Conclusion***

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Zeev Kitov whose current telephone number is (571) 272 - 2052. The examiner can normally be reached on 8:00 – 4:30. If attempts to reach examiner by telephone are unsuccessful, the examiner's supervisor, Brian Sircus can be reached on (571) 272 – 2800, Ext. 36. The fax phone number for organization where this application or proceedings is assigned is (703) 872-9306 for all communications.

Z.K.  
04/01/2005



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